

<b>Notice of References Cited</b>	Application/Control No. 10/054,354	Applicant(s)/Patent Under Reexamination LAWTON ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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*	N	WO 99/13720	03-1999		Rikihisa et al.	
	O					
	P					
	Q					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Waner et al (J Ve. Diagn Invest. 12:240-244, 2000).
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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